
**Form 1449 (Modified)**
**Information Disclosure  
Statement By Applicant**

(Use Several Sheets if Necessary)

 Atty Docket No.  
KLA1P041/P773

 Application No.:  
09/990,171

 Applicant:  
Nasser-Ghodsi et al.  
Filing Date  
November 21, 2001

 Group  
Not Assigned

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
JK	A	6,108,398	08/22/00	Mazor et al.			07/13/98
JK	B	6,351,516	02/26/02	Mazor et al.			12/14/99
	C						
	D						
	E						
	F						
	G						
	H						
	I						

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication		
	O			
	P			
	Q			
Examiner		Date Considered	11/07/2003	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PATENT &  
TRADEMARK OFFICE**Form 1449 (Modified)****Information Disclosure  
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Atty Docket No.  
KLA1P041/P773Application No.:  
09/990,171Applicant:  
Mehran Nasser-Ghodsi, et al.Filing Date  
November 21, 2001Group  
2882**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
IK	1A	6,421,122	07/16/02	Nara, et al.			04/11/01

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	1B							

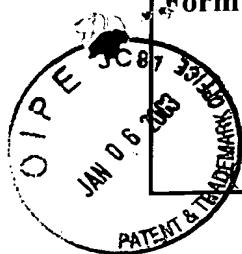
**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	1C	
	2C	
	3C	
	4C	

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Examiner	<i>M. Nasser-Ghodsi</i>	Date Considered	<i>15/07/2003</i>
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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
JK	1A	4,162,528	07/24/79	Maldonado et al.			03/31/78
	2A	4,476,386	10/09/84	Reid et al.			06/10/81
	3A	4,534,049	08/06/85	Koga			08/10/83
	4A	4,675,889	06/23/87	Wood et al.			07/08/85
	5A	4,777,364	10/11/88	Sartore			06/15/87
	6A	4,885,465	12/05/89	Nagatsuka et al			07/05/88
	7A	4,959,848	09/25/90	Parobek			12/16/87
	8A	5,055,679	10/08/91	Ninomiya et al.			01/03/90
	9A	5,065,020	11/12/91	Kanda			11/20/90
	10A	5,299,252	03/29/94	Takahashi			04/07/93
	11A	5,350,921	09/27/94	Aoyama et al.			07/23/93
	A12	5,485,499	01/16/96	Pew et al.			08/05/94
	A13	5,530,732	06/25/96	Takemi			05/19/95
	A14	5,596,195	01/21/97	Obori et al.			09/15/95
	A15	5,656,812	08/12/97	Takahashi			07/19/96
	A16	5,657,363	08/12/97	Hossain et al.			10/10/95
	A17	5,754,620	05/19/98	Hossain et al.			09/13/96
	A18	5,777,336	07/07/98	Silver et al.			10/03/95
	A19	5,866,903	05/09/97	Morita et al.			05/09/97
	A20	5,892,809	04/06/99	Wittry			09/08/98
	A21	5,060,247	10/22/91	Watanabe			11/15/89
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	A26	4,962,516	10/09/90	Soezima			
	A27	5,703,361	12/30/97	Sartore			
JK	A28	5,926,522	07/20/99	McCarthy et al.			

Examiner

*Dr. K. K. Khandpur*

Date Considered

*11/07/2003*

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Application No.:

09/990,711

Applicant:

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Filing Date

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## Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	1B	6-267485	09/22/94	Japan			X	

## Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
JK	2B	J.L. Pouchou and F. Pichoir, "Electron Probe X-Ray Microanalysis Applied To Thin Surface Films and Stratified Specimens", Scanning Microscopy, Supplement 7., (1993), pp. 167-189.
	3B	"High-Resolution X-ray Microanalysis for Low Voltage Applications", NORAN INSTRUMENTS, (1997), 5 pages
	4B	M. Stavrev <sup>a</sup> , D. Fischer <sup>a</sup> , C. Wenzel <sup>a</sup> , and T. Heiser <sup>b</sup> , "Study OF Ta(N,O) diffusion barrier stability: analytical and electrical characterization of low level Cu contamination in Si", MICROELECTRONIC ENGINEERING, 37/38 (1997) pp. 245-251
	5B	JeanLouis Pouchou, "X-Ray microanalysis of stratified specimens", Elsevier Science Publishers B.V., Analytica Chimica Acta. 283 (1993) pp. 81-97
	6B	Schiebl et al., "A characteristic fluorescence correction factor for use in electron probe microanalysis", Microsc. Microanal, Microstruct. 2, 1991, pp. 413-423
	7B	S. Sevov et al., "A comparison of recently developed correction procedures for electron probe microanalysis", Scanning , 1989, vol. 11, pp. 123-134
	8B	August et al., "A method for determining the mass thickness of thin films using electron probe microanalysis", Scanning, 1987, vol. 9, pp. 145-155
	9B	August et al., "Energy distribution of electrons transmitted through thin foils", Institut fur Angewandte aund Technische Physik, Technische Universitat Wien Wiedner Hauptstr.8-10, A-1040 Wien (Vienna), Austria
	10B	Pfeiffer et al., "Models and their implementation", CEC-Vienna Reports, No. 92-08, December, 1992.
	11B	'MuFilm Data Collection & K-Ratio Measurement Documentation", pp. 2-10
JK	12B	August et al., "Calculation and Comparison of the Surface Ionization", Institut fur Angewandte und Technische Physik, Technische Universitat Wien, Wiedner Hauptstr. 8-10, A-1040 Wien (Vienna), Austria
Examiner	<i>Dr. J. Kukusacka</i>	Date Considered 11/07/2003

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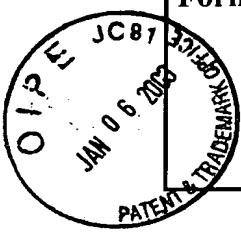
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## Other Documents

<input checked="" type="checkbox"/>	1C	✓ August et al., "Calculation and Comparison of the Backscattering Factor R for Characteristic X-Ray Emission", Scanning, 1988, vol. 10, pp. 107-113
<input checked="" type="checkbox"/>	2C	✓ August et al., "The Backscattering Factor as a Part of the Correction Procedures Employed in Quantitative Electron Probe Microanalysis", Radex-Rundschau, 1988, pp. 624-637.
<input checked="" type="checkbox"/>	3C	✓ August et al., "Calculation of the electron backscattering coefficient for thin films using a simple electron scattering model", J. Microsc. Spectrosc. Electron., 1989, vol. 14, pp. 189-201.
<input checked="" type="checkbox"/>	4C	✓ August, et al., "Theoretical prediction of the electron backscattering coefficient for multilayer structures", Journal of Microscopy, February 1990, vol. 157, pp. 247-254.
Examiner	<i>Dr. Kutschabre</i>	
	Date Considered	11/07/2003

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